Search Notes



Application/Control No.	Applicant(s)/Patent (	Applicant(s)/Patent under Reexamination	
10/705,937	CHEN, WEN-TSAN	CHEN, WEN-TSAN	
Examiner	Art Unit		
Matthew G. Kayrish	2653		

SEARCHED				
Class	Subclass	Date	Examiner	
369	77.1	10/5/2005	мĸ	
720	607	10/5/2005	MK	
369	77.2	10/6/2005	MK	
369	77.1	10/6/2005	мк	
369	247	10/6/2005	MK	
369	263	10/6/2005	MK	
369	77.1	10/7/2005	MK	
369	77.1	10/7/2005	MK	
369	247	10/7/2005	MK	
369	263	10/7/2005	MK	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
720	604	10/28/2005	MK	
720	607	10/28/2005	МК	
EAST (See attached search notes) (USPG-PUB Text Search)		10/28/2005	мк	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (See attached search notes) (USPG-PUB, USOCR, USPAT)	10/5/2005	МК		
EAST (See attached search notes) (USPG-PUB, USOCR, USPAT)	10/6/2005	мк		
EAST (See attached search notes) (USPG-PUB, USOCR, USPAT)	10/7/2005	MK		
EAST (See attached search notes) (USPG-PUB, USOCR, USPAT)	10/11/2005	MK		
EAST (See attached search notes) (EPO, JPO, DERWENT)	10/12/2005	мк		
EAST (See attached search notes) (EPO, JPO, DERWENT)	10/26/2005	MK		